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#### 1 Development of an access-by-the-Internet control laboratory

*Fisher, J.; Hoye, W.S.; Koehler, J.; Lian, R.; Zongli Lin;*  
Decision and Control, 2001. Proceedings of the 40th IEEE Conference on , Vol 3 , 4-7 Dec. 2001

Pages:2827 - 2832 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(901 KB\)\]](#) **IEEE CNF**

#### 2 Networking remote instrumentation for the Advanced Light Source

*Chin, M.; Hinkson, J.; Magyary, S.;*  
Particle Accelerator Conference, 1989. 'Accelerator Science and Technology',  
Proceedings of the 1989 IEEE , 20-23 March 1989  
Pages:1648 - 1650 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(316 KB\)\]](#) **IEEE CNF**

#### 3 Innovative aspects of the SDL control system

*Graves, W.S.; Feng, S.K.; Pearson, P.S.; Smith, J.D.;*  
Particle Accelerator Conference, 1997. Proceedings of the 1997 , Volume: 2 , May 1997  
Pages:2437 - 2439 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) **IEEE CNF**

#### 4 Developments in 'standard' test gear

*Erskine, G.;*  
Instrumentation in Electronic Product Manufacture, IEE Colloquium on , 5 May

Pages:1/1 - 1/3

[Abstract] [PDF Full-Text (120 KB)] IEE CNF

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